


Search Notes 	Application/Control No. 10585711	Applicant(s)/Patent Under Reexamination FALCIONI ET AL.
	Examiner Nay Tun	Art Unit 2612

SEARCHED

Class	Subclass	Date	Examiner
340	657, 585, 679, 660, 664, 539.1, 539.24	05/16/2009	CGC
379	106.01	05/16/2009	CGC
340	585, 657-664, 539.1, 539.22, 539.24, 545.6, 3.1, 3.3, 3.32, 3.42-3.44, 3.9	05/13/2010	NT
702	182-185, 187-189	05/13/2010	NT
62	127	05/13/2010	NT
340	585, 657-664, 539.1, 539.22, 539.24, 545.6, 3.1, 3.3, 3.32, 3.42-3.44, 3.9	12/01/2010	NT
702	182-185, 187-189	12/01/2010	NT
62	127	12/01/2010	NT
340	585, 657-664, 539.1, 539.22, 539.24, 545.6, 3.1, 3.3, 3.32, 3.42-3.44, 3.9	6/17/2011	NT
702	182-185, 187-189	6/17/2011	NT
62	127	6/17/2011	NT

SEARCH NOTES

Search Notes	Date	Examiner
PLUS Search	05/15/2009	CGC
Inventor/Assignee Search	05/16/2009	CGC
Daniel Wu	05/18/2009	CGC
EAST Search Printout	05/1/20098	CGC
updated search on EAST (USPAT, USPGUPG, EPO, JPO, DERWENT, IBM_TDB) - See search history print out	12/15/2009	N.T.
updated search on EAST (USPAT, USPGUPG, EPO, JPO, DERWENT, IBM_TDB) - See search history print out	5/13/2010	NT
updated search on EAST (USPAT, USPGUPG, EPO, JPO, DERWENT, IBM_TDB) - See search history print out	12/01/2010	NT
updated search on EAST (USPAT, USPGUPG, EPO, JPO, DERWENT, IBM_TDB) - See search history print out	6/17/2011	NT

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

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Examiner, Art Unit 2612